

Single 8-Channel/Differential 4-Channel CMOS Analog Multiplexers

June 1994

Features

- This Circuit Is Processed in Accordance to MIL-STD-883 and is Fully Conformant Under the Provisions of Paragraph 1.2.1.
- ON-Resistance 100Ω Maximum (+25°C)
- Low Power Consumption ($P_D < 11\text{mW}$)
- Fast Switching Action
 - $t_{\text{TRANS}} < 250\text{ns}$
 - $t_{\text{ON/OFF(EN)}} < 150\text{ns}$
- Low Charge Injection
- Upgrade from DG508A/DG509A
- TTL, CMOS Compatible
- Single or Split Supply Operation

Applications

- Data Acquisition Systems
- Audio Switching Systems
- Automatic Testers
- Hi-Rel Systems
- Sample and Hold Circuits
- Communication Systems
- Analog Selector Switch

Description

The DG408/883 Single 8-Channel and DG409/883 Differential 4-Channel monolithic CMOS analog multiplexers are drop-in replacements for the popular DG508A and DG509A series devices. They each include an array of eight analog switches, a TTL/CMOS compatible digital decode circuit for channel selection, a voltage reference for logic thresholds and an ENABLE input for device selection when several multiplexers are present.

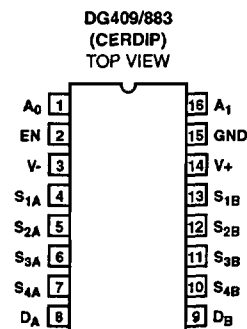
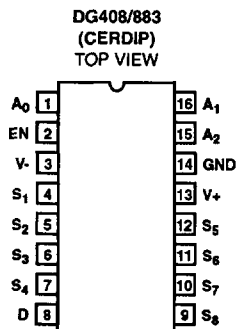
The DG408/883 and DG409/883 feature lower signal ON resistance ($< 100\Omega$) and faster switch transition time ($t_{\text{TRANS}} < 250\text{ns}$) compared to the DG508A or DG509A. Charge injection has been reduced, simplifying sample and hold applications. The improvements in the DG408/883 series are made possible by using a high-voltage silicon-gate process. An epitaxial layer prevents the latch-up associated with older CMOS technologies. Power supplies may be single-ended from +5V to +34V, or split from $\pm 5\text{V}$ to $\pm 20\text{V}$.

The analog switches are bilateral, equally matched for AC or bidirectional signals. The ON resistance variation with analog signals is quite low over a $\pm 5\text{V}$ analog input range.

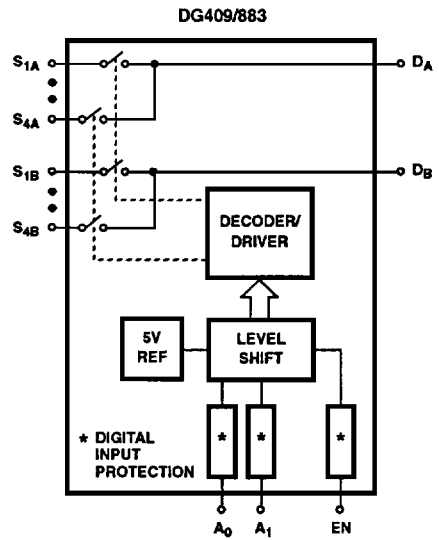
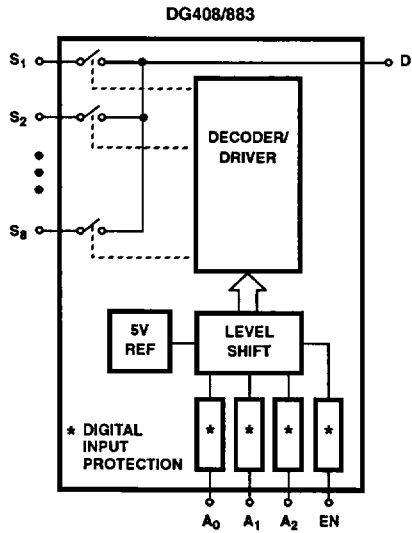
Ordering Information

PART NUMBER	TEMPERATURE RANGE	PACKAGE
DG408AK/883	-55°C to +125°C	16 Lead CerDIP
DG409AK/883	-55°C to +125°C	16 Lead CerDIP

Pinouts



Functional Block Diagrams



DG408/883, DG409/883

Pin Description - (DG408/883)

PIN	SYMBOL	DESCRIPTION
1	A ₀	Logic Decode Input (Bit 0, LSB)
2	EN	Enable Input
3	V-	Negative Power Supply Terminal
4	S ₁	Source (Input) for Channel 1
5	S ₂	Source (Input) for Channel 2
6	S ₃	Source (Input) for Channel 3
7	S ₄	Source (Input) for Channel 4
8	D	Drain (Output)
9	S ₈	Source (Input) for Channel 8
10	S ₇	Source (Input) for Channel 7
11	S ₆	Source (Input) for Channel 6
12	S ₅	Source (Input) for Channel 5
13	V+	Positive Power Supply Terminal (Substrate)
14	GND	Ground Terminal (Logic Common)
15	A ₂	Logic Decode Input (Bit 2, MSB)
16	A ₁	Logic Decode Input (Bit 1)

Pin Description - (DG409/883)

PIN	SYMBOL	DESCRIPTION
1	A ₀	Logic Decode Input (Bit 0, LSB)
2	EN	Enable Input
3	V-	Negative Power Supply Terminal
4	S _{1A}	Source (Input) for Channel 1A
5	S _{2A}	Source (Input) for Channel 2A
6	S _{3A}	Source (Input) for Channel 3A
7	S _{4A}	Source (Input) for Channel 4A
8	D _A	Drain A (Output A)
9	D _B	Drain B (Output B)
10	S _{4B}	Source (Input) for Channel 4B
11	S _{3B}	Source (Input) for Channel 3B
12	S _{2B}	Source (Input) for Channel 2B
13	S _{1B}	Source (Input) for Channel 1B
14	V+	Positive Power Supply Terminal
15	GND	Ground Terminal (Logic Common)
16	A ₁	Logic Decode Input (Bit 1, MSB)

TRUTH TABLE DG408/883

A ₂	A ₁	A ₀	EN	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

TRUTH TABLE DG409/883

A ₁	A ₀	EN	ON SWITCH
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

NOTES:

1. V_{AH} Logic "1" ≥2.4V.
2. V_{AL} Logic "0" ≤0.8V.

Specifications DG408/883, DG409/883

Absolute Maximum Ratings

V+ to V-+44.0V
GND to V- 25V
Digital Inputs (Note 1) (V-) -2V to (V+) + 2V or 20mA, Whichever Occurs First
Current (Any Terminal, Except S or D)30mA
Continuous Current, S or D20mA
Peak Current, S or D (Pulsed 1ms, 10% Duty Cycle)40mA
Storage Temperature Range -65°C to +125°C
Lead Temperature (Soldering, 10s) +300°C

Thermal Information

Thermal Resistance	θ_{JA}	θ_{JC}
CerDIP Package	70°C/W	20°C/W
Operating Temperature	-55°C to +125°C	
Junction Temperature	+175°C	

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, V+ = +15V, V- = -15V, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Drain-Source ON Resistance	$r_{DS(ON)}$	$V_D = \pm 10V, V_{AL} = 0.8V, V_{AH} = 2.4V, I_S = -10mA,$ Sequence Each Switch On	1, 3	+25°C, -55°C	-	100	Ω
			2	+125°C	-	125	Ω
Difference In Drain-Source ON Resistance Between Channels	$\Delta r_{DS(ON)}$	$V_D = \pm 10V, V_{AL} = 0.8V, V_{AH} = 2.4V, I_S = -10mA,$ (Note 2)	1	+25°C	-	15	Ω
Source OFF Leakage Current	$I_{S(OFF)}$	$V_S = \pm 10V, V_D = \mp 10V, V_{EN} = 0V$	1	+25°C	-0.5	+0.5	nA
			2	+125°C	-50	+50	nA
Drain OFF Leakage Current DG408/883 DG409/883	$I_{D(OFF)}$	$V_S = \pm 10V, V_D = \mp 10V, V_{EN} = 0V$	1	+25°C	-1	+1	nA
			2	+125°C	-200	+200	nA
			1	+25°C	-1	+1	nA
			2	+125°C	-100	+100	nA
Drain ON Leakage Current DG408/883 DG409/883	$I_{D(ON)}$	$V_S = V_D = \pm 10V, V_{AL} = 0.8V, V_{AH} = 2.4V, V_{EN} = 2.4V,$ Sequence Each Switch On	1	+25°C	-1	+1	nA
			2	+125°C	-200	+200	nA
			1	+25°C	-1	+1	nA
			2	+125°C	-150	+150	nA
Logic Input Current, Input Voltage High	I_{AH}	$V_{EN} = 0.8V, V_A = 2.4V$	1, 2, 3	+25°C, +125°C, -55°C	-10	+10	μA
		$V_{EN} = 0.8V, V_A = 15V$			-10	+10	μA
Logic Input Current, Input Voltage Low	I_{AL}	$V_{EN} = 0V, V_A = 0V$	1, 2, 3	+25°C, +125°C, -55°C	-10	+10	μA
		$V_{EN} = 2.4V, V_A = 0V$			-10	+10	μA
Positive Supply Current Standby	$I_{+(SB)}$	$V_{EN} = 0V, V_A = 0V$	1, 2, 3	+25°C, +125°C, -55°C	-	75	μA

5
CMOS ANALOG MULTIPLEXERS

Specifications DG408/883, DG409/883

TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)

Device Tested at: $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $V_+ = +15\text{V}$, $V_- = -15\text{V}$, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Negative Supply Current Standby	$I_{(SB)}$	$V_{EN} = 0\text{V}$, $V_A = 0\text{V}$	1, 2, 3	+25°C, +125°C, -55°C	-75	-	μA
Positive Supply Current	I+	$V_{EN} = 2.4\text{V}$, $V_A = 0\text{V}$	1, 3	+25°C, -55°C	-	0.5	mA
			2	+125°C	-	2	mA
Negative Supply Current	I-	$V_{EN} = 2.4\text{V}$, $V_A = 0\text{V}$	1, 2, 3	+25°C, +125°C, -55°C	-0.5	-	mA

TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $V_+ = +15\text{V}$, $V_- = -15\text{V}$, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Switching Time of Multiplexer	t_{TRANS}		9, 10, 11	+25°C, +125°C, -55°C	-	250	ns
Enable Turn ON Time	$t_{ON(EN)}$		9, 11	+25°C, -55°C	-	150	ns
			10	+125°C	-	225	ns
Enable Turn OFF Time	$t_{OFF(EN)}$		9, 10, 11	+25°C, +125°C, -55°C	-	150	ns
Break-Before-Make Interval	t_{OPEN}		9	+25°C	10	-	ns

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS

Table 3 Intentionally Left Blank.

TABLE 4. ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUPS (SEE TABLES 1 AND 2)
Interim Electrical Parameters (Pre Burn-In)	1
Final Electrical Test Parameters	1 (Note 3), 2, 3, 9, 10, 11
Group A Test Requirements	1, 2, 3, 9, 10, 11
Groups C and D Endpoints	1

NOTES:

1. Signals on S_X , D_X , or IN_X exceeding V_+ or V_- will be clamped by internal diodes. Limit forward diode current to maximum current ratings.
2. $\Delta r_{DS(ON)} = r_{DS(ON)} \text{ MAX} - r_{DS(ON)} \text{ MIN}$.
3. PDA applies to Subgroup 1 only.

Die Characteristics

DIE DIMENSIONS:

1800 μ m x 3320 μ m x 485 \pm 25 μ m

METALLIZATION:

Type: SiAl

Thickness: 12k \AA \pm 1k \AA

GLASSIVATION:

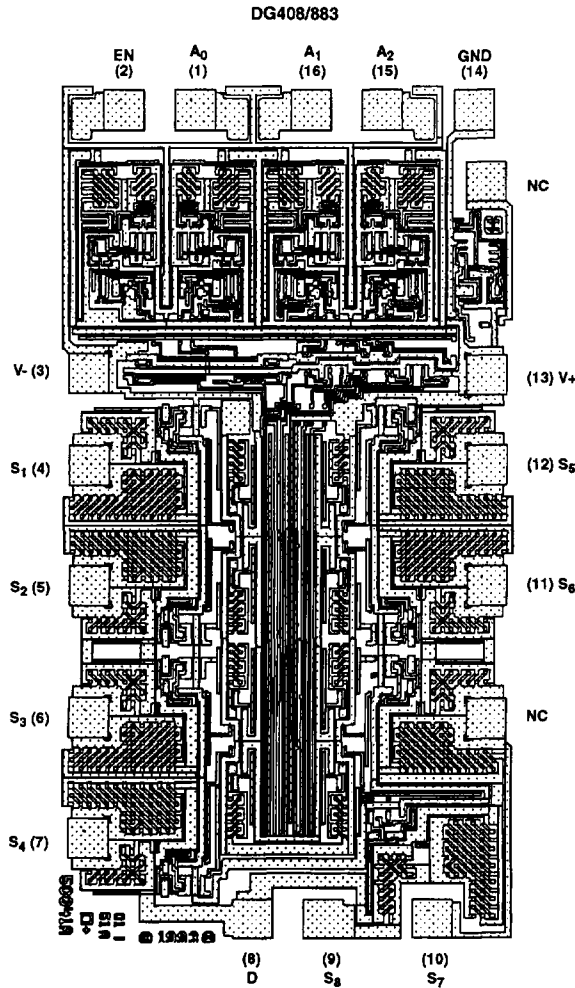
Type: Nitride

Thickness: 8k \AA \pm 1k \AA

WORST CASE CURRENT DENSITY:

9.1 x 10⁴ A/cm²

Metallization Mask Layout



5
CMOS ANALOG
MULTIPLIXERS

Die Characteristics

DIE DIMENSIONS:

1800 μ m x 3320 μ m x 485 \pm 25 μ m

METALLIZATION:

Type: SiAl
 Thickness: 12k \AA \pm 1k \AA

GLASSIVATION:

Type: Nitride
 Thickness: 8k \AA \pm 1k \AA

WORST CASE CURRENT DENSITY:

9.1 x 10⁴ A/cm²

Metallization Mask Layout

